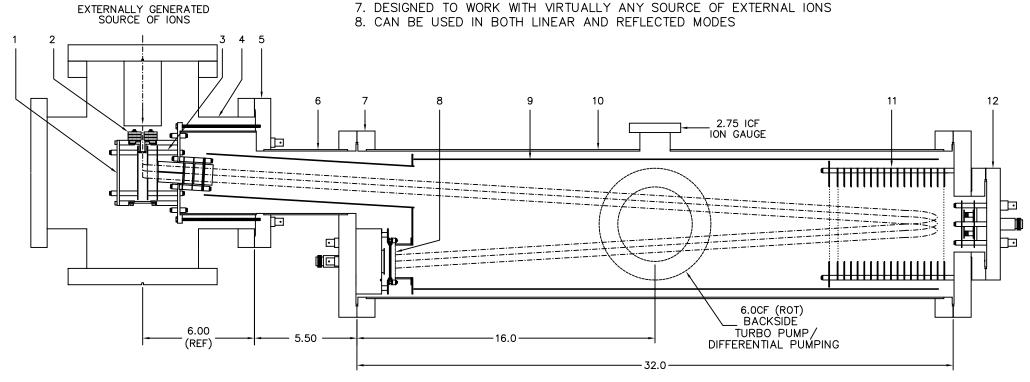
- 1. MODULAR, EASY TO MAINTAIN, UPGRADE
- 2. EXISTING INSTRUMENTS CAN BE EASILY RETROFITTED
- 3. DEFLECTION/FOCUS OPTICS TILTED PARALLEL TO ION BEAM
- 4. DEFLECTION/FOCUS OPTICS ABLE TO CORRECT FOR VARYING ENERGIES OF INCOMING IONS
- 5. EXTRACTION REGION IS DIFFERENTIALLY PUMPED
- 6. EXTRACTION REGION HAS ACCESS PORTS FOR EMT OR INTERNAL IONIZATION
- 7. DESIGNED TO WORK WITH VIRTUALLY ANY SOURCE OF EXTERNAL IONS
- 8. CAN BE USED IN BOTH LINEAR AND REFLECTED MODES



- 1. B-682 SHROUD/SHIELD/DIFFERENTIAL PUMPING
- 2. FOCUS OPTICS/COLLIMATOR
- 3. ION EXTRACTION/DEFLECTION/FOCUSING OPTICS
- 4. C-685 TEST CHAMBER
- 5. 8 ICF (ROT) SOURCE MOUNTING FLANGE
- 6. C-854 OFFSET ADAPTOR
- 7. 10 ICF FLANGE
- 8. C-726 40MM MCP Z-GAP OR DUAL DETECTOR ASSY.
- 9. D-679 FLIGHT TUBE LINER/SHIELD
- 10. C-855 FLIGHT TUBE ASSY.
- 11. C-852 REFLECTOR ASSY.
- 12. C-701 18MM MCP DUAL DETECTOR ASSY.

ORTHOGONAL ACCELERATION TOF JORDAN TOF PRODUCTS, INC. DUAL OR Z-GAP MCP DETECTOR REV 7-25-09